for all  $R_1 \neq R_1^*$ . In other words,  $R_1^*$  is the critical region which yields the minimum Bayes' risk for the least favorable  $P(H_0)$ . Assuming that the minimization and maximization operations are interchangeable, then we have

$$\min_{R_1} \max_{P(H_0)} \bar{C}[P(H_0), R_1] = \max_{P(H_0)} \min_{R_1} \bar{C}[P(H_0), R_1]$$
(8.25)

The minimization of  $C[P(H_0), R_1]$  with respect to  $R_1$  is simply the Bayes' test, so that

$$\min_{n} \bar{C}[P(H_0), R_1] = C^*[P(H_0)] \tag{8.26}$$

where  $C^*[P(H_0)]$  is the minimum Bayes' risk associated with the a priori probability  $P(H_0)$ . Thus, Eq. (8.25) states that we may find the minimax test by finding the Bayes' test for the least favorable  $P(H_0)$ , that is, the  $P(H_0)$  which maximizes  $\bar{C}[P(H_0)]$ .

## Solved Problems

## HYPOTHESIS TESTING

8.1. Suppose a manufacturer of memory chips observes that the probability of chip failure is p = 0.05. A new procedure is introduced to improve the design of chips. To test this new procedure, 200 chips could be produced using this new procedure and tested. Let r.v. X denote the number of these 200 chips that fail. We set the test rule that we would accept the new procedure if  $X \le 5$ . Let

 $H_0$ : p = 0.05 (No change hypothesis)  $H_1$ : p < 0.05 (Improvement hypothesis)

Find the probability of a Type I error.

If we assume that these tests using the new procedure are independent and have the same probability of failure on each test, then X is a binomial r.v. with parameters (n, p) = (200, p). We make a Type I error if  $X \le 5$  when in fact p = 0.05. Thus, using Eq. (2.37), we have

$$P_1 = P(D_1 \mid H_0) = P(X \le 5; p = 0.05)$$

$$= \sum_{k=0}^{5} {200 \choose k} (0.05)^k (0.95)^{200-k}$$

Since n is rather large and p is small, these binomial probabilities can be approximated by Poisson probabilities with  $\lambda = np = 200(0.05) = 10$  (see Prob. 2.40). Thus, using Eq. (2.100), we obtain

$$P_1 \approx \sum_{k=0}^{5} e^{-10} \frac{10^k}{k!} = 0.067$$

Note that  $H_0$  is a simple hypothesis but  $H_1$  is a composite hypothesis.

8.2. Consider again the memory chip manufacturing problem of Prob. 8.1. Now let

 $H_0$ : p = 0.05 (No change hypothesis)  $H_1$ : p = 0.02 (Improvement hypothesis)

Again our rule is, we would reject the new procedure if X > 5. Find the probability of a Type II error.